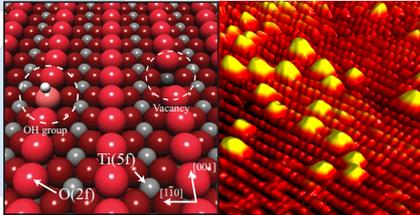




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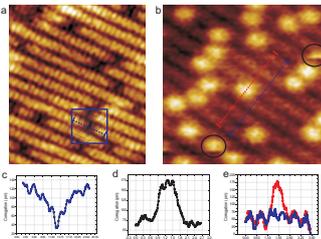
# Seeing atomic defects

## Benchmark oxide



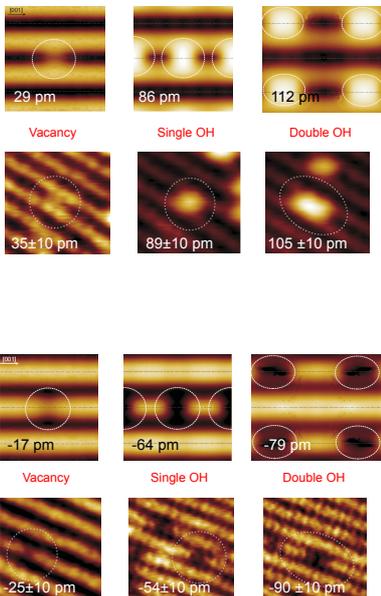
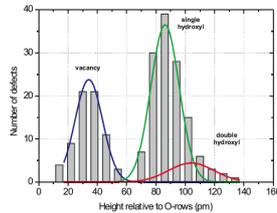
- TiO<sub>2</sub> remains a model oxide for many surface science studies, particularly for Scanning Probe Microscopy (SPM).

## nc-AFM



- Even in UHV, residual adsorbates can be seen on the surface after a few hours.
- Rows match TiO<sub>2</sub> (110) surface, but what about the atoms, defects and adsorbates?

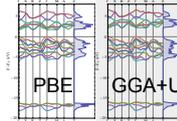
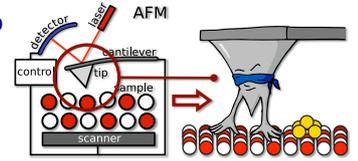
- Statistical analysis reveals three types of defect contrast – can we prove these are linked to characteristic defects on the surface?



- Simulations with a negative tip match “protrusion” contrast.
- Contrast magnitude agrees with experiment for defect usual suspects.
- Simulations with a positive tip match “hole” contrast.

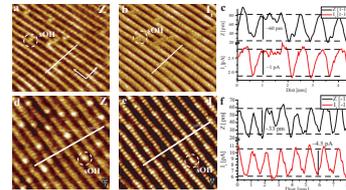
## Methods

- Experimental feedback loop on frequency change, while topography and current is measured.



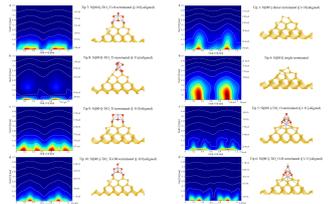
- First principles simulations, with multiple scattering theory for tunneling.

## Simultaneous STM/AFM



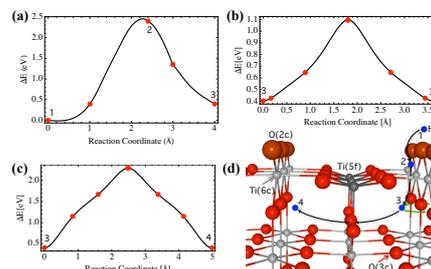
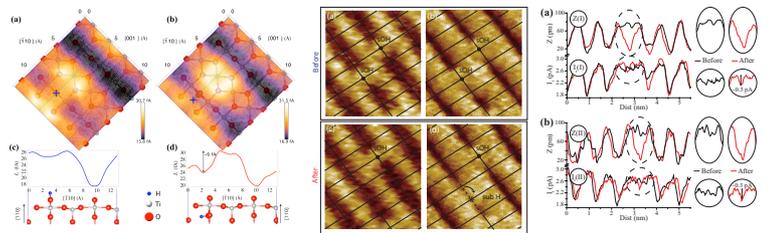
- Identification of surface species provided by AFM.
- Three modes observed.

- Registry between STM and AFM images is very sensitive to the type of tip – STM and AFM images can be in- and out-of-phase.



- Powerful tool for understanding contrast and studying further defects or adsorbates.

## Hydrogen manipulation



- Subsurface hydrogen invisible in AFM, but seen in STM.
- Combined STM/AFM records manipulation of H from surface to subsurface site.